Metric between buckling structures and elastic properties in physisorbed polymer-tethered lipid monolayers

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Figure S1. (A) Histogram of heights determined at each pixel for 10 mol% DSPE-PEG monolayer. (B) Cumulative histogram of pixel heights. (B-insert) AFM micrograph of 10 mol% DSPE-PEG5000 with bearing area cutoff shown by color: fraction to the left of bearing area cutoff arrow indicated in AFM micrograph in blue; fraction to the right indicated in red.
Figure S2. Analysis of section width determination. A) Typical section width analysis for 10% DSPE-PEG5000 monolayer. B) AFM micrograph showing location of width determination. Lines between sections = 349 nm. C Histogram of data acquired from 10% DSPE-PEG monolayer. Mean = 350 nm.

Figure S32. SOPC bilayers with 5 (A), 10 (B), 30 (C) and 40 (D) mol% DSPE-PEG5000. Scale bar = 10 μm.